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Dated: Oct 19, 2009

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EXHIBIT A

<u>Our Ref.</u>	<u>AMD Ref.</u>	<u>Filing Date</u>	<u>Serial No.</u>	<u>Issued Date</u>	<u>Patent No.</u>	<u>Title</u>	<u>Inventor</u>
5800-33300	F0996	3/23/2001	09/816,706	2/7/2006	6,996,124	Mechanism to Strip LARQ Header and Regenerate FCS to Support Sleep Mode Wake Up	Chow
5800-33400	TT4390	4/19/2001	09/838,652			Determining Logon Status in a Broadband Network System and Automatically Restoring Logon Connectivity	Kyle, Schmidt
5800-33500	F1018	7/2/2002	10/190,088			Method and System for Optimizing the Design of a Network Controller	Gaspar
5800-33600	F1011	3/26/2002	10/107,386			Signaling a Network State Change Among Stations in a Home Phoneline Networking Alliance Media Access Controller (HPNA MAC)	Chow, Karighattam
5800-33700	F1006	12/20/2001	10/028,507			Signal Validation Testing for a Home Phoneline Networking Alliance Media Access Controller (HPNA MAC)	Cooper, Gaspar
5800-33800	C493397	9/29/1997	08/940,691			Method and System for Prevention of Sputtering of a High Conductivity Metal During Via Etch of a Metal Interconnect	Gupta, Chen
5800-33900	H2393	5/15/2007	11/748,743			Methods of Forming Silicides of Different Thicknesses on Different Structures	Yu, Besser, Yang, Yu, Chan
5800-34000	H2406	12/19/2006	11/613,006			Design Rules Checking Augmented with Pattern Matching	Dai, Yang, Rodriguez, Capodieci
5800-34100	H1775	3/1/2004	10/790,590	6/2/2009	7,543,256	System and Method for Designing an Integrated Circuit Device	Lukanc, Tabery, Capodieci, Babcock, Kim, Spence, Haidinyak
5800-34200	NY0128	4/5/2007	11/696,862			Electrically Programmable Reticle and System	Miller
5800-34900	F0857	5/7/2002	09/850706			Method and Apparatus for Monitoring Optical Properties of Anti-Reflective Coatings for Integrated Circuits	Singh, Bhanwar; Hui, Angela T.; Morales, Carmen; Subramanian, Ramkumar

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5800-35000	H0982	2/5/2004	10/773026	12/25/2007	7312125	Fully Depleted Strained Semiconductor on Insulator Transistor and Method of Making the Same	Xiang, Qi; Besser, Paul R.; Ngo, Minh Van; Paton, Eric N.; Wang, Haihong
5800-35001	H0982DIV	12/6/2007	11/999818			Fully Depleted Strained Semiconductor on Insulator Transistor and Method of Making the Same	Xiang, Qi; Besser, Paul R.; Ngo, Minh Van; Paton, Eric N.; Wang, Haihong
5800-35100	H0960PRV	9/30/2002	60/4515179			SIGE/SI Stack Gate Electrode to Improve NI Polycide for MOSFET	Paton, Eric N.; Xiang, Qi; Besser, Paul R.; Lin, Ming-Ren; Ngo, Minh V.; Wang, Haihong
5800-35102	H0960	12/31/2002	10/335492	9/7/2004	6787864	MOSFETS Incorporating Nickel Germanosilicided Gate And Methods For Their Formation	Paton, Eric N.; Xiang, Qi; Besser, Paul R.; Lin, Ming-Ren; Ngo, Minh V.; Wang, Haihong
5800-35200	H0959 PRV	9/30/2002	60/415,226			FINFET Device Incorporating Strained Silicon In The Channel Region	Lin, Ming-Ren; Goo, Jung-Suk; Wang, Haihong; Xiang, Qi
5800-35201	H0959	12/31/2002	10/335474	10/5/2004	6800910	FINFET Device Incorporating Strained Silicon In The Channel Region	Lin, Ming-Ren; Goo, Jung-Suk; Wang, Haihong; Xiang, Qi
5800-35300	H1725	2/2/2004	10/769835	4/29/2008	7364962	Shallow Trench Isolation Process Utilizing Differential Liners	Krishnan, Srinath

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5800-35301	H1725DIV	3/13/2008	12/047636			Shallow Trench Isolation Process Utilizing Differential Liners	Krishnan, Srinath
5800-35302	H1725DIV-CNT	8/7/2009	12/538,008			Shallow Trench Isolation Process Utilizing Differential Liners	Krishnan, Srinath
5800-35400	H1731	9/3/2003	10/654631	7/18/2006	7078299	Formation Of FINFET Using A Sidewall Epitaxial Layer	Maszara, Witold P.; Goo, Jung-Suk; Pan, James N.; Xiang, Qi
5800-35500	F0822	6/25/2001	09887035	10/12/2004	6803178	Two Mask Photoresist Exposure Pattern For Dense And Isolated Regions	Subramanian, Ramkumar; Bell, Scott A.; Lukanc, Todd P.; Plat, Marina V.; Okoroanyanwu, Uzodinma; Kim, Hung-Eil
5800-35501	F0822DIV	8/24/2004	10/925123	5/6/2008	7368225	Two Mask Photoresist Exposure Pattern For Dense And Isolated Regions	Subramanian, Ramkumar; Bell, Scott A.; Lukanc, Todd P.; Plat, Marina V.; Okoroanyanwu, Uzodinma; Kim, Hung-Eil
5800-35600	H2175	4/4/2005	11/098262	5/26/2009	7538026	Multilayer Low Reflectivity Hard Mask And Process Therefor	Ghandehari, Kouros; Minvielle, Anna M.; Plat; Marina V.; Tokuno, Hirokazu
5800-35601	H2175DIV	5/19/2009	12/468715			Multilayer Low Reflectivity Hard Mask And Process Therefor	Ghandehari, Kouros; Minvielle, Anna M.; Plat; Marina V.; Tokuno, Hirokazu